



S O S G R O U P

**NANOSPEC 6100UV Film Measurement Tool**  
**SN 0307-0083**  
**150mm Configuration**

# NANOSPEC 6100UV Film Measurement Tool

## 75mm to 200mm Configuration

Location warehouse Nijmegen condition “as is where is”



Model: Nanospec 6100

Utilizes non-contact spectroscopic reflectometry to measure sites as small as 10um in diameter

Computerized 1um resolution stage

Autofocus

Provides automatic generation of film thickness uniformity maps in high resolution color and 3D formats

Measurement range: 200 Å - 30um with visible light source

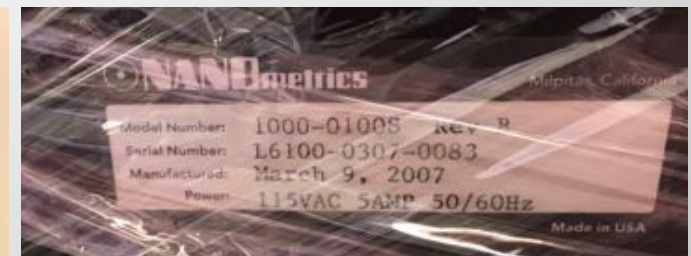
Continuous scanning from 210 - 800 nanometers

System Computer and Software

System Monitor, Keyboard, and Trackball

2D & 3D wafer mapping software

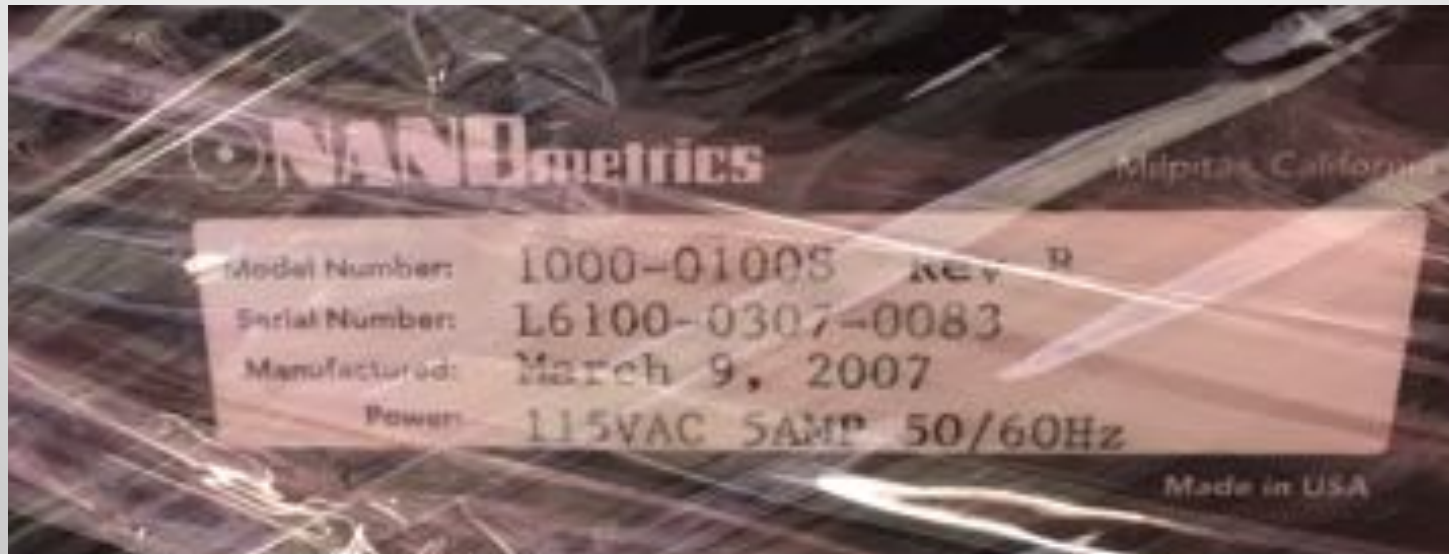
Operator Manual and Documentation



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# Solutions on Silicon BV

*Your service partner for LAM Research Equipment*

- **Equipment Support**  
PM, CM, Trouble shooting, Upgrading, Training and Onsite Service Contracts
- **Process Support**  
Process design, Improvement, Fab-to-Fab Transfer and Integration
- **Refurbishment**  
From custom to complete refurbishment
- **Relocation**  
Auditing, Fingerprinting, Decommissioning, Installation, Acceptance
- **Materials**  
Supplier of first class second source materials

